Supporting Information

Evidence of Negative Capacitance in Piezoelectric ZnO Thin Films Sputtered on Interdigital Electrodes

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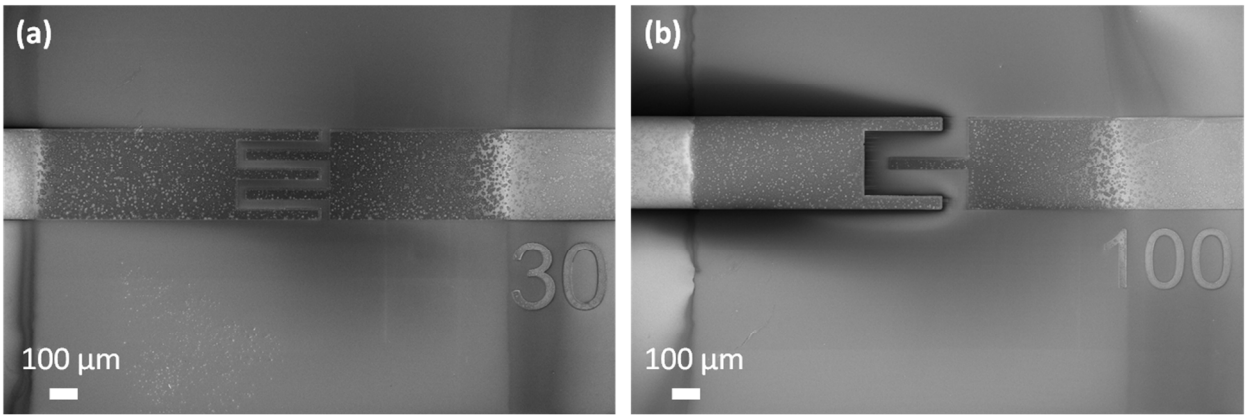

Figure S1. FESEM images of ZnO thin films sputtered on (a) 30 µm-distanced, and (b) 100 µm-distanced IDEs.

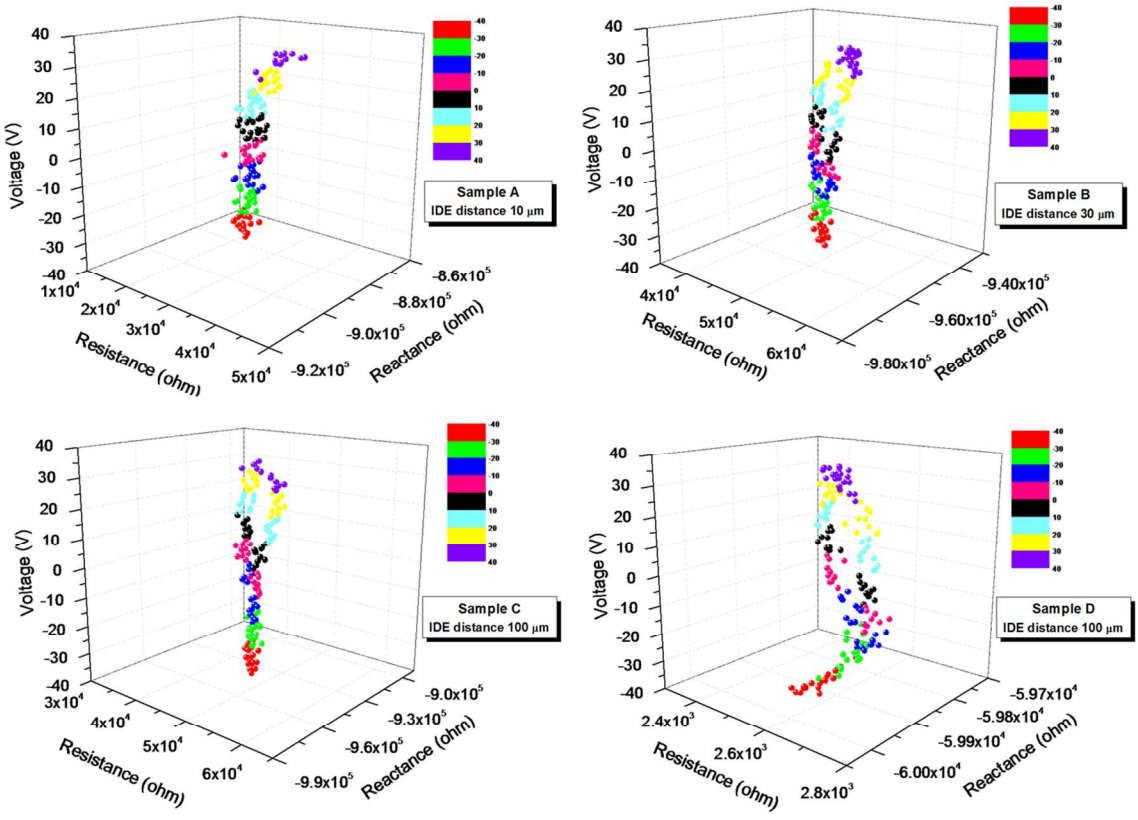

Figure S2. Phase plots of sputtered ZnO thin films deposited on different IDE geometries. Signal frequency 10 kHz. The color bar indicates the DC voltage range.

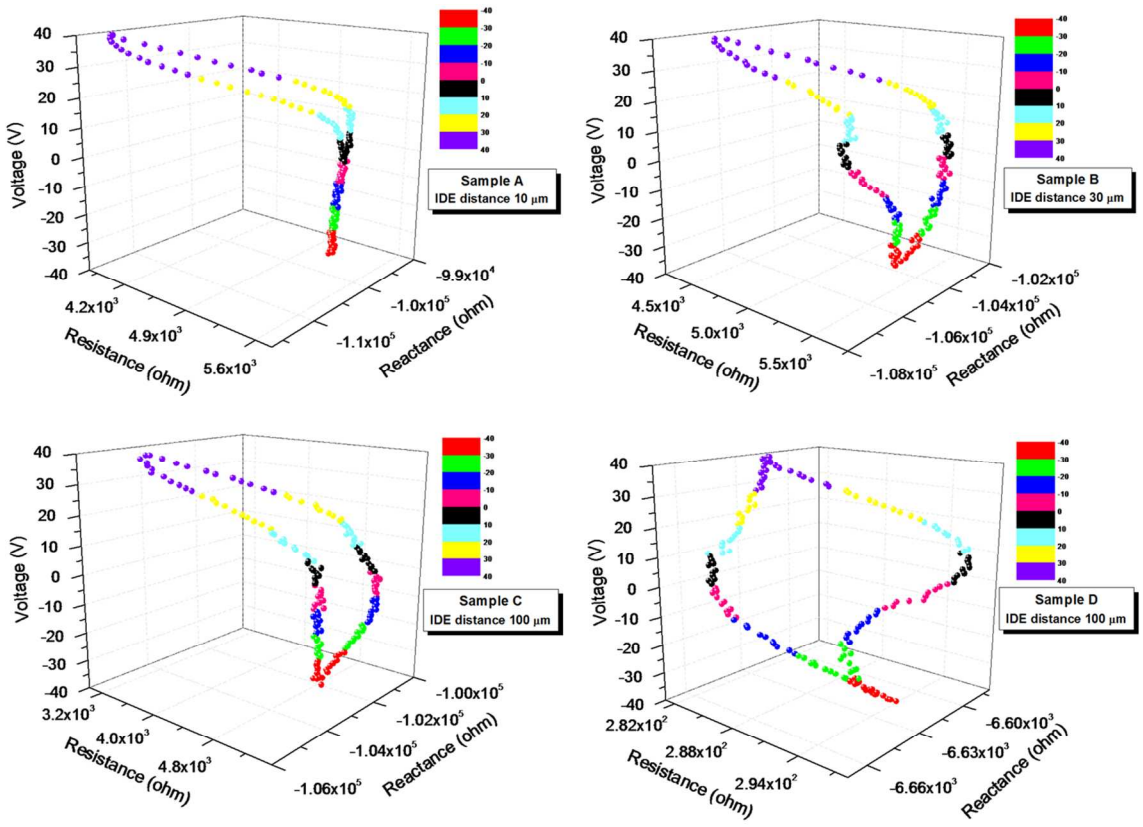

Figure S3. Phase plots of sputtered ZnO thin films deposited on different IDE geometries. Signal frequency 100 kHz. The color bar indicates the DC voltage range.